

EDX-9000



EDX-9000, X-ray Fluorescence Spectrometer

More accurate test result is the unremitting pursuit of MRC; meanwhile, we constantly bear in mind to provide customers with superior service. The newly developed EDX-9000 exactly upholds the concept. It not only inherits the merits of MRC EDX series, but also adopts the most advanced detection technology (X-SDD), which reduces test time to only 1 second. In addition, EDX-9000 also introduces MRC patented product – precise positioning system, which can realize image coordinated control, multi-point continuous test. The new electric sample chamber makes operation easier, and the new designed automatic sample platform guarantees accurate detection.

Performance Characteristics:

- The most advanced detection technology – Silicon Drift Detector (SDD), with resolution as low as 125eV
Advantage: large detecting area (25mm²); receiving more information in unit time; better count rate and resolution; higher precious metal detection efficiency; better SNR and lower detection limit
- The most advanced digital multichannel technology
Advantage: effectively improve output efficiency, realize ultra high counting rate, guarantee effective counting rate higher than 300KCPS
- Large power X ray tube and sophisticated collimation filter system
Advantage: higher excitation efficiency for precious metals
- Optical shutter system
Advantage: no need to close high voltage when replacing sample; improve test efficiency and accuracy.

Fine positioning system

- Ultra-HD industrial camera shows test points more clearly
- Multi-point test
- 2D movable sample platform – supports image coordinated control, multi-point continuous test
- Tiny sample detection – minimum 0.2mm
- 8 collimators and 4 filters provide free selection according to different sample
- The smallest 0.2 mm collimator allows detecting tiny sample
- It identifies 99.9% and 99.99% pure gold effectively
- It can detect hazardous elements in precious metals like Pb, Cd.

Humanized Design

- Safer: X-ray integrated safety device – optical shutter interacts with interlock; housing is linked with high voltage enable terminal
- Faster: multipoint test, to test the clicking point
- Preset test: it can start test at fixed time based on time setting
- Preset preheating after starting up: customers can preset time of auto start. At the same time, preheating, automatic check, correction can be done automatically. You can also preset time of auto stop and set sound and light alarm before stop.

Application Fields:

- RoHS testing
- Mining and alloy (Cu, stainless steel and so on) componential analysis
- Measurement of plating thickness, measurement of electroplate liquid and plating content
- The content test of precious metal such as gold, platinum and silver & different kinds of jewelry
- Mainly applied in RoHS directive industries, precious metals and jewelries processing industries; banks, jewelry shops and test institutes; electroplating industries.

Configuration:

- X-Silicon Drift Detector (X-SDD)
- Digital multichannel analytic system
- X ray source
- High and low voltage power supply
- Collimation filter system
- Precise sample platform
- Optical shutter system
- Sample observation system
- Electronic control system
- PC and ink-jet printer.

Model	EDX-9000
Analytical range	from S to U
Stability (RSD)	0.02%
Detector	X-Silicon Drift Detector (X-SDD)
Resolution	≤135eV
Tube current	≤1000uA
Tube voltage	5 ~ 50kV
Measuring time	1s (default)
Filter	4 filters
Collimator	8 collimators
Sample observation	HD industrial camera
Humidity	≤70%
Temperature	15°C ~ 30°C
Input voltage	AC 220V±5V (suggest to use AC stabilizer)